# **Power MOSFET**

60 V, 63 A, 12.4  $m\Omega$ 

#### **Features**

- Low R<sub>DS(on)</sub>
- High Current Capability
- Avalanche Energy Specified
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Units
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	e – Contin	uous	$V_{GS}$	±20	V
Gate–to–Source Voltage – Non–Repetitive (t <sub>p</sub> = 10 μs)			$V_{GS}$	±30	V
Continuous Drain	Steady	T <sub>C</sub> = 25°C	I <sub>D</sub>	63	Α
Current – $R_{\theta JC}$ (Note 1)	State	T <sub>C</sub> = 100°C		45	
Power Dissipation –			$P_{D}$	107	W
R <sub>θJC</sub> (Note 1)	State $T_C = 1$	T <sub>C</sub> = 100°C		54	
Pulsed Drain Current	t <sub>p</sub> =	= 10 μs	I <sub>DM</sub>	252	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	–55 to 175	°C
Source Current (Body Diode) Pulsed			I <sub>S</sub>	63	Α
Single Pulse Drain-to Source Avalanche			EAS	80	mJ
Energy – (L = 0.1 mH)			IAS	40	Α
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T <sub>L</sub>	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Units
Junction-to-Case (Drain) - Steady State (Note 1)	$R_{\theta JC}$	1.4	°C/W
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	33	°C/W

1

1. Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [2 oz] including traces).

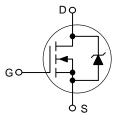


## ON Semiconductor®

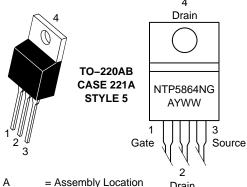
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX (Note 1)
60 V	12.4 mΩ @ 10 V	63 A

## N-Channel



# MARKING DIAGRAM & PIN ASSIGNMENT



Y = Year

WW = Work Week
G = Pb-Free Package

#### **ORDERING INFORMATION**

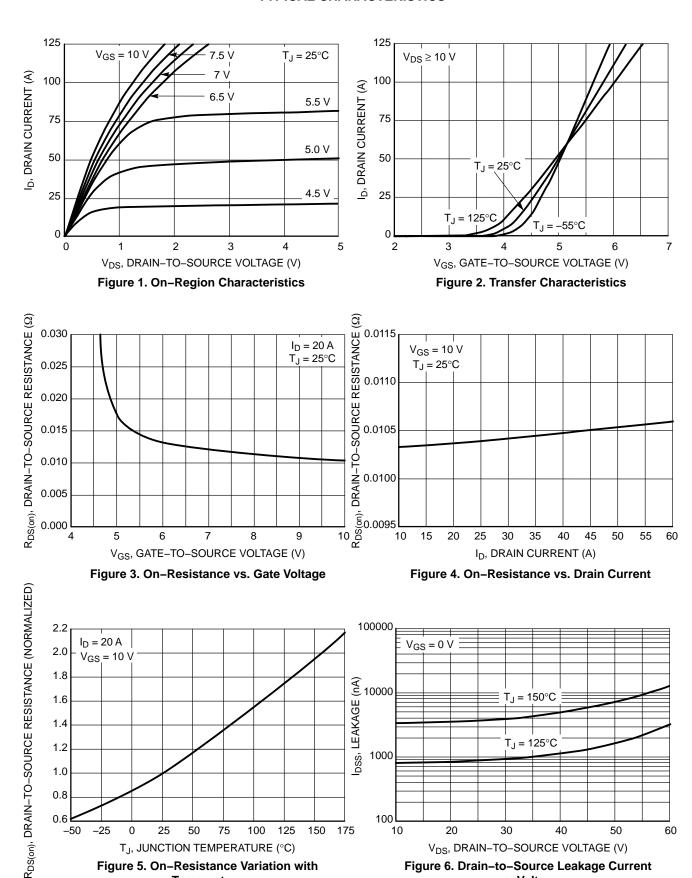
Device	Package	Shipping
NTP5864NG	TO-220 (Pb-Free)	50 Units / Rail

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•		•		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				58		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 60 V	T <sub>J</sub> = 25°C			1.0	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$				±100	nA
ON CHARACTERISTICS (Note 2)							•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{E}$	ο = 250 μΑ	2.0		4.0	V
Gate Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-10		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V,	I <sub>D</sub> = 20 A		10.2	12.4	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V,	I <sub>D</sub> = 20 A		10		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>ISS</sub>				1680		pF
Output Capacitance	C <sub>OSS</sub>	$V_{GS} = 0 \text{ V, f} = V_{DS} = 2$	: 1.0 MHz, 25 V		189		
Reverse Transfer Capacitance	C <sub>RSS</sub>	- 503			124		
Total Gate Charge	Q <sub>G(TOT)</sub>				31		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 48 \text{ V},$ $I_{D} = 20 \text{ A}$			2.0		
Gate-to-Source Charge	$Q_{GS}$				7.3		
Gate-to-Drain Charge	$Q_{GD}$				10		
Gate Resistance	$R_g$				0.5		Ω
SWITCHING CHARACTERISTICS, $V_0$	<sub>SS</sub> = 10 V (Note	3)					
Turn-On Delay Time	t <sub>d(ON)</sub>				10		ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 10 V, V	<sub>DD</sub> = 48 V,		6.4		
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 20 \text{ A}, R_G = 2.5 \Omega$			18		
Fall Time	t <sub>f</sub>				4.6		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0 V$	T <sub>J</sub> = 25°C		0.94	1.2	V
		I <sub>S</sub> = 40 A	T <sub>J</sub> = 125°C		0.84		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{SD}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 20 \text{ A}$			24		ns
Charge Time	t <sub>a</sub>				16		
Discharge Time	t <sub>b</sub>				7.9		
Reverse Recovery Charge	Q <sub>RR</sub>				20		nC

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



T<sub>J</sub>, JUNCTION TEMPERATURE (°C) Figure 5. On-Resistance Variation with Temperature

75

50

25

8.0 0.6

-25

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V) Figure 6. Drain-to-Source Leakage Current vs. Voltage

30

40

50

60

175

125

150

100

100

10

20

#### **TYPICAL CHARACTERISTICS**

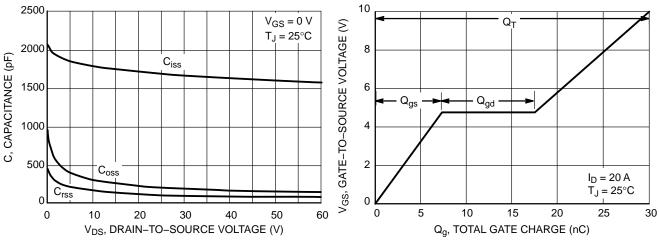


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source vs. Total Charge

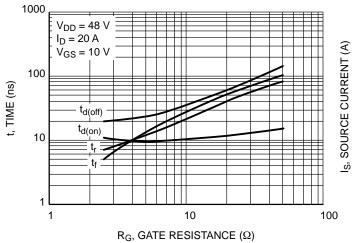


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

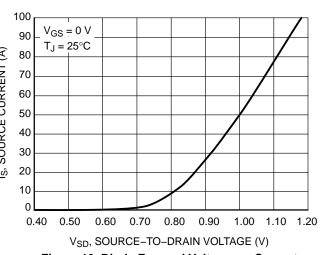


Figure 10. Diode Forward Voltage vs. Current

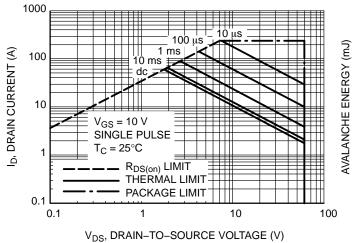


Figure 11. Maximum Rated Forward Biased Safe Operating Area

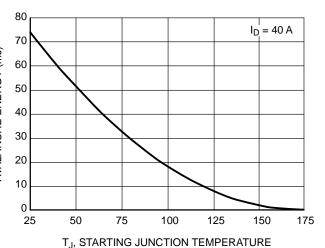


Figure 12. Maximum Avalanche Energy versus
Starting Junction Temperature

## **TYPICAL CHARACTERISTICS**

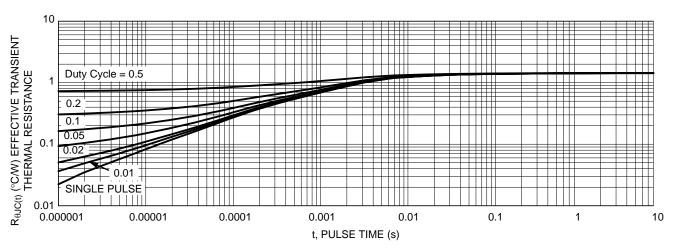
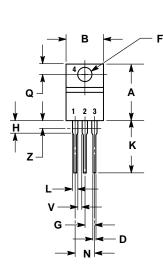
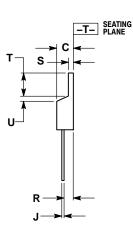


Figure 13. Thermal Response

#### PACKAGE DIMENSIONS

TO-220 CASE 221A-09 **ISSUE AH** 





#### NOTES

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.415	9.66	10.53
С	0.160	0.190	4.07	4.83
D	0.025	0.038	0.64	0.96
F	0.142	0.161	3.61	4.09
G	0.095	0.105	2.42	2.66
Н	0.110	0.161	2.80	4.10
J	0.014	0.024	0.36	0.61
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
T	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
٧	0.045		1.15	
Z		0.080		2.04

STYLE 5:

PIN 1. GATE DRAIN 2.

- SOURCE
- DRAIN

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